


<b>Search Notes</b> 	<b>Application/Control No.</b> 10619584	<b>Applicant(s)/Patent Under Reexamination</b> KIM ET AL.
	<b>Examiner</b> JOHN HEYMAN	<b>Art Unit</b> 2871

SEARCHED			
Class	Subclass	Date	Examiner
349	43, 54, 139	12/17/2008	JSH

SEARCH NOTES		
Search Notes	Date	Examiner
Text search Class 349/43, 54, 139	12/17/2008	JSH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
349	See Search History	12/17/2008	JSH

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